查询SN74CBT16213供应商

捷多邦,专业PCB打样工厂,24小时加**会NF**4CBT16213 24-BIT FET BUS-EXCHANGE SWITCH

SCDS026G - MAY 1995 - REVISED MAY 2000

- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Input Levels
- Package Options Include Plastic Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV), and Shrink Small-Outline (DL) Packages

description

The SN74CBT16213 provides 24 bits of high-speed TTL-compatible bus switching or exchanging. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

The device operates as a 24-bit bus switch or a 12-bit bus exchanger that provides data exchanging between the four signal ports via the data-select (S0–S2) terminals.

The SN74CBT16213 is characterized for operation from –40°C to 85°C.

,	iv, or d (top vi	DL PACKAGE EW)
S0 [56 S1 56
1A1	2	55 S2
1A2	3	54 1B1
2A1	4	53 B1B2
2A1		52 2B1
3A1 [6	51 2B2
3A2 [7	50 3B1
GND	-	49 GND
4A1 [9	48 3B2
4A2	10	47 4B1
5A1 🛛	11	46 4B2
5A2 [12	45 5B1
6A1	13	44 5B2
6A2	14	43 6B1
7A1	15	42 6B2
7A2 🛛	16	41 7B1
	17	40 7B2
8A1 [18	39 8B1
GND [19	38 GND
8A2 🛛	20	37 8B2
9A1 🛛	21	36 9B1
9A2 🛛	22	35 9B2
10A1 🛛	23	34 010B1
10A2 🛛	24	33 10B2
11A1	25	32 11 11 11
11A2	26	31 11B2
12A1	27	30 12B1
12A2 L	28	29 12B2

FUNCTION TABLE

- 1	INPUT	S	INPUTS/0	OUTPUTS	FUNCTION
S2	S1	S0	A1	A2	FUNCTION
L	L	L	Z	Z	Disconnect
L	L	Н	B1	Z	A1 port = B1 port
L	Н	L	B2	Z	A1 port = B2 port
L	Н	Н	Z	B1	A2 port = B1 port
н	L	L	Z	B2	A2 port = B2 port
н	L	Н	A2 and B2 A1 and B2		A1 port = A2 port = B2 port
н	н	ozsc	B1	B2	A1 port = B1 port A2 port = B2 port
н	Н	н	B2	B1	A1 port = B2 port A2 port = B1 port

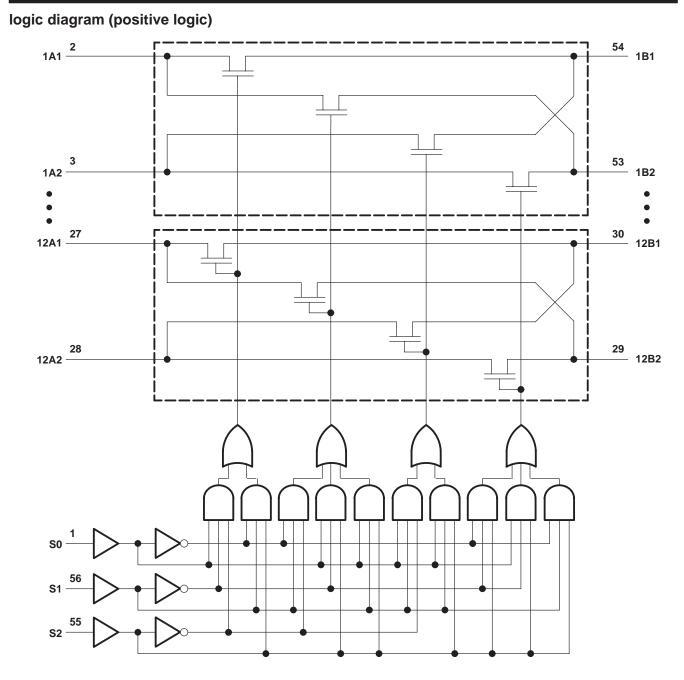


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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range. Vcc	
	-0.5 V to 7 V
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
Vcc	Supply voltage	4	5.5	V
VIH	High-level control input voltage	2		V
VIL	Low-level control input voltage		0.8	V
ТА	Operating free-air temperature	-40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER		TEST CONDIT	IONS	MIN	TYP‡	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	l _l = –18 mA				-1.2	V	
		V _{CC} = 0,	VI = 5.5 V				10		
ł		V _{CC} = 5.5 V,	$V_{I} = 5.5 V \text{ or GND}$				±1	μA	
ICC		V _{CC} = 5.5 V,	IO = 0,	$V_I = V_{CC}$ or GND			3	μA	
∆I _{CC} §	Control inputs	V _{CC} = 5.5 V,	One input at 3.4 V,	Other inputs at V_{CC} or GND			2.5	mA	
Ci	Control inputs	V _I = 3 V or 0				4.5		pF	
0	B port				8.5		~F		
Cio(OFF)	Cio(OFF) A port	V _O = 3 V or 0,	S0, S1, or S2 = V_{CC}			8		pF	
		$V_{CC} = 4 V$, TYP at $V_{CC} = 4 V$	V _I = 2.4 V,	lj = 15 mA		14	20		
A to B or B to A ron¶ A1 to A2	V _{CC} = 4.5 V	V ₁ = 0	lj = 64 mA		5	7			
			lj = 30 mA		5	7			
			V _I = 2.4 V,	lj = 15 mA		8	15	Ω	
	A1 to A2	VC	$V_{CC} = 4 V$, TYP at $V_{CC} = 4 V$	V ₁ = 2.4 V,	l _l = 15 mA		22	30	32
			N/- 0	lı = 64 mA		10	14		
		$V_{CC} = 4.5 V \qquad \qquad V_{I} = 0$	v] = 0	lj = 30 mA		10	14		
			V _I = 2.4 V,	lj = 15 mA		16	22		

[‡] All typical values are at $V_{CC} = 5 V$ (unless otherwise noted), $T_A = 25^{\circ}C$.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

¶ Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.



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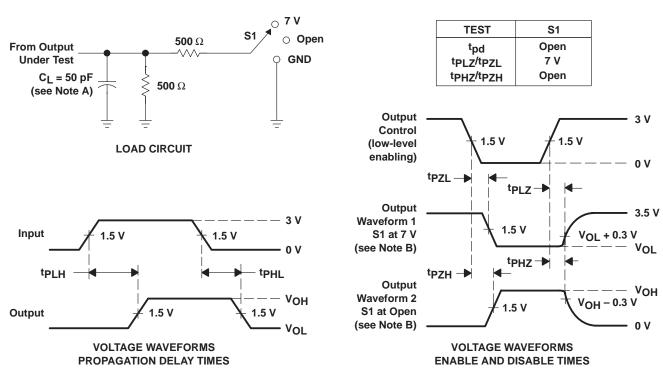
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switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4 V	V _{CC} = 5 V ± 0.5 V		UNIT
			MIN MAX	MIN	MAX	
. +	A or B	B or A	0.35		0.25	
t _{pd} †	A1	A2	0.5		0.5	ns
t _{en}	S	A or B	12.4	3.2	11.1	ns
^t dis	S	A or B	12.4	2.3	11.9	ns
ten	S0	A2 and B2	11.5	4	10.9	ns
^t dis	SO	A2 and B2	12.8	5.7	12	ns

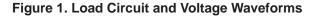
[†] The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns. t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. tpzL and tpzH are the same as ten.
- G. tPLH and tPHL are the same as tpd.





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